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<input type="checkbox"/>	L1	chip with (moisture or corrosion) with circuit	647

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moisture and detection and circuit

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Aerospace Conference, 1997. Proceedings., IEEE , Volume: 4 , 1-8 Feb. 1997

Pages:277 - 283 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(504 KB\)\]](#) **IEEE CNF****2 An ac impedance in situ methodology for assessing high reliability performance of plastic encapsulated microelectronics in harsh environments***Lumsden, J.; Kuo, J.; Pollock, G.;*

Electronic Components and Technology Conference, 2002. Proceedings. 52nd , 28-31 May 2002

Pages:219 - 224

[\[Abstract\]](#) [\[PDF Full-Text \(677 KB\)\]](#) **IEEE CNF****3 Critical issues in thin layer acoustic image interpretation and metrology for microelectronics***Canumalla, S.;*

Electronic Components and Technology Conference, 2002. Proceedings. 52nd , 28-31 May 2002

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[\[Abstract\]](#) [\[PDF Full-Text \(1297 KB\)\]](#) **IEEE CNF****4 The use of time domain spectroscopy as a diagnostic tool for rotating machine windings***David, E.; Lamarre, L.; Nguyen, D.N.;*

Electrical Insulation, 2002. Conference Record of the 2002 IEEE International Symposium on , 7-10 April 2002

Pages:506 - 510